

DATA SHEET

Model DHS50A12

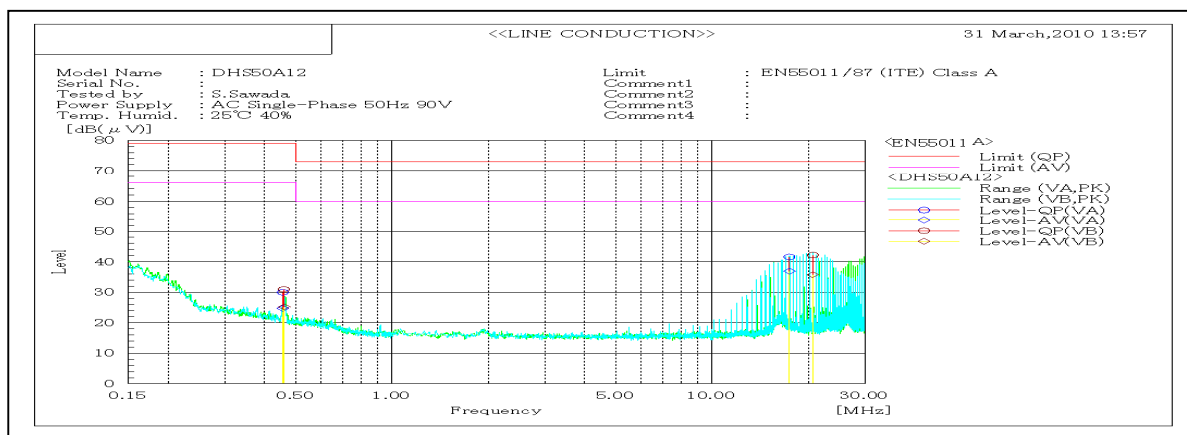
Date 27-Apr-10

Test EMI
Line conduction & Radiated emission

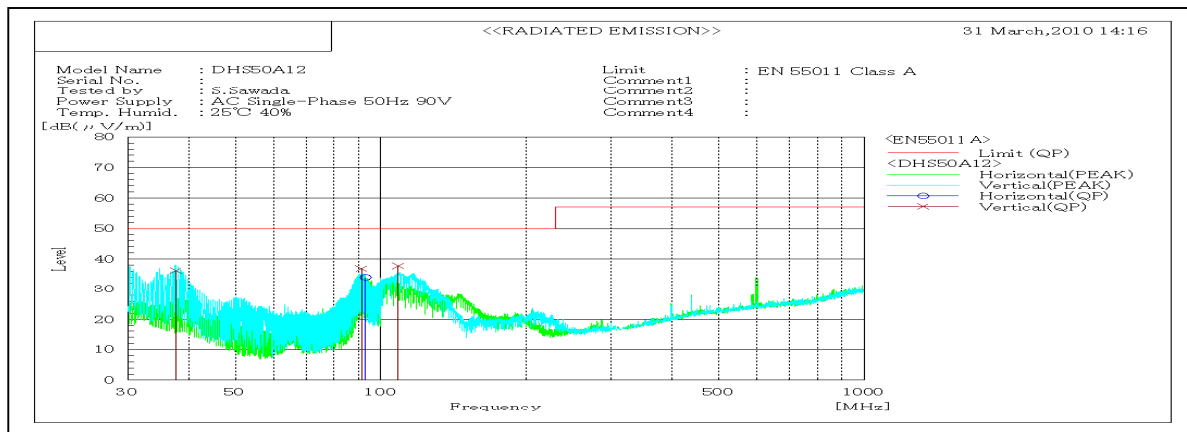
Temp. 25 degreeC

Humid. 40 %RH

Tested by S.Sawada



Frequency MHz	Harm	Line Phase	Reading dB(μV)		Factor dB	Level dB(μV)		Limit dB(μV)		Margin dB		Pass/ Fail	Remark
			QP	AV		QP	AV	QP	AV	QP	AV		
0.45595		VA	20	14.7	10	30	24.7	79	66	49	41.3	Pass	
0.4596		VB	20.9	15.2	10	30.9	25.2	79	66	48.1	40.8	Pass	
17.4415		VA	31	26.3	10.6	41.6	36.9	73	60	31.4	23.1	Pass	
20.6534		VB	31.5	25.1	10.7	42.2	35.8	73	60	30.8	24.2	Pass	

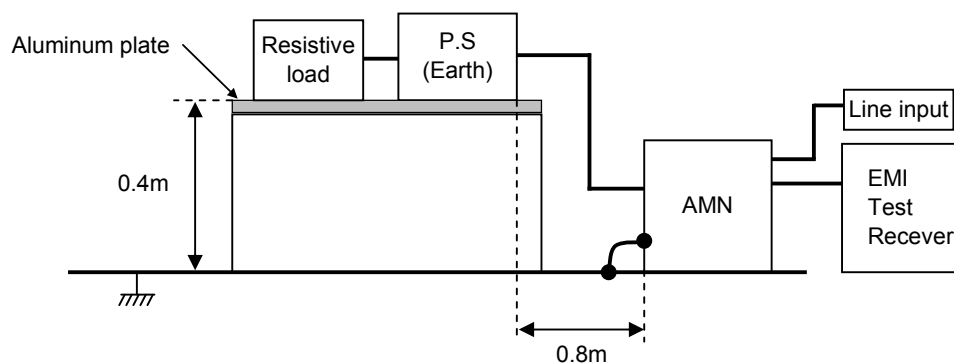


Frequency MHz	Harm	Polariz ation	Level Check	Stabili ty	Reading dB(μV)			Space Loss dB	Level dB(mW)			Limit dB(mW)	Limit dB(mW)	Limit dB(mW)	Margin dB			Pass/ Fail	Height cm	Angle deg	Remark
					QP	AV	PK		QP	AV	PK				QP	AV	PK				
37.574		V		Stable	49.5			-13.3	36.2			50			13.8			Pass	109	251	
91.216		V		Stable	55.6			-18.7	36.9			50			13.1			Pass	129	117	
93.018		H		Stable	52.5			-18.5	34			50			16			Pass	141	91	
108.602		V		Stable	54.4			-16.7	37.7			50			12.3			Pass	153	94	

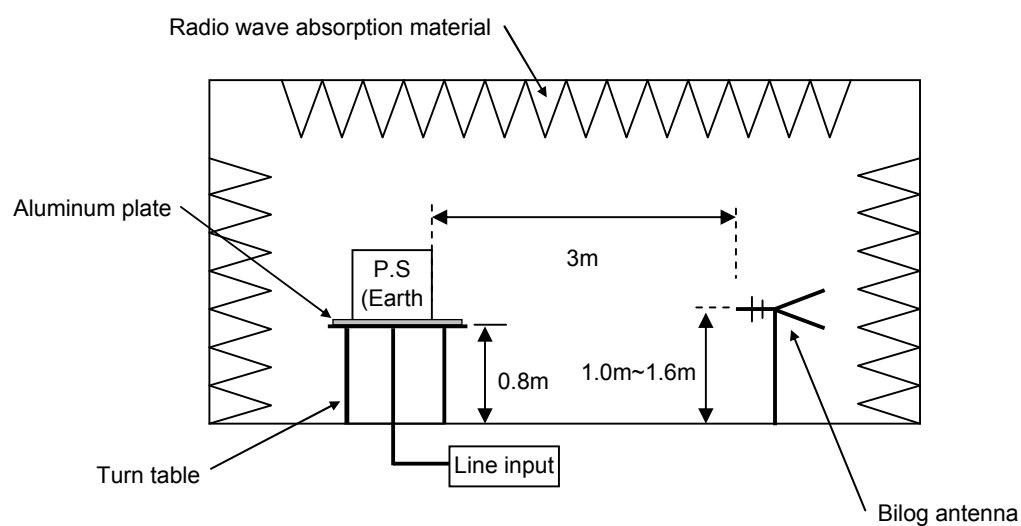
DATA SHEET

Model	Circuit used for measurement
Test	EMI Line conduction & Radiated emission

1. Line conduction



2. Radiated emission

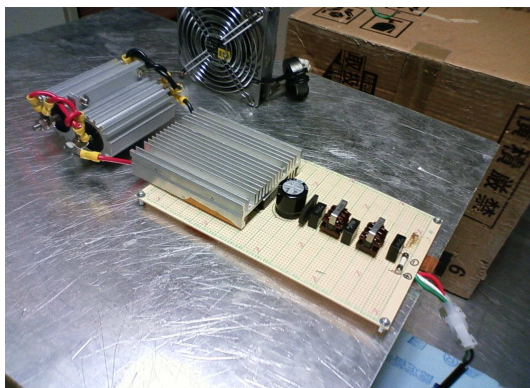


Test: EMI

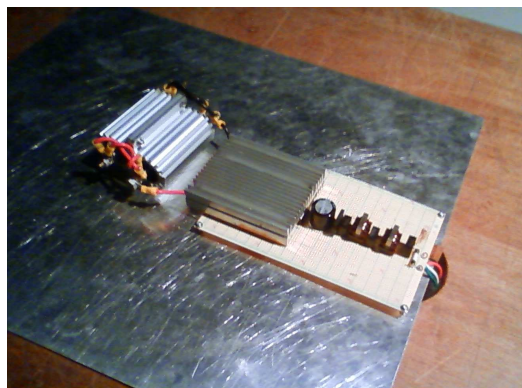
Model Name:DHS50A/DHS100A Series

○ Photographs of Test Set-Up

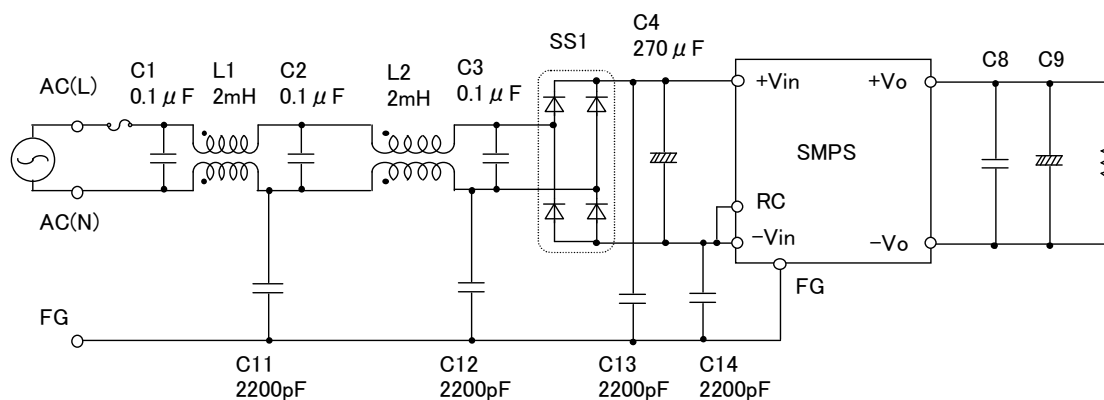
LINE CONDUCTION



RADIATED EMISSION



○ Test circuit



L1,L2	:	SC-05-200(NEC TOKIN)
SS1	:	D3SBA60(SINDENGEN)
C8	:	DHS50A24/DHS100A24 4.7 μ F
	:	Others 10 μ F
C9	:	DHS50A05/DHS100A05 2200 μ F
	:	DHS50A12/DHS100A12 470 μ F
	:	DHS50A15/DHS100A15 470 μ F
	:	DHS50A24/DHS100A24 220 μ F